

<b>Notice of References Cited</b>	Application/Control No. 10/573,252		Applicant(s)/Patent Under Reexamination EBIKO ET AL.	
	Examiner THANH C. LE		Art Unit 2618	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2008/0051044	02-2008	Takehara, Hiroyasu	455/127.2
*	B	US-2006/0046764	03-2006	Ohba et al.	455/522
*	C	US-2005/0243909	11-2005	Itahara et al.	375/240
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